

Total No. of Questions : 8]

SEAT No. :

P3613

[Total No. of Pages : 2

**[4959]-1099**

**B.E. (E & TC)**

**Nano Electronics and MEMS  
(2012 Pattern) (Semester - II)**

**Time : 2½ Hours]**

**[Max. Marks : 70**

**Instructions to the candidates:**

- 1) Answer any one question out of Q.1 or Q.2, Q.3 or Q.4, Q.5 or Q.6, Q.7 or Q.8.
- 2) Neat diagrams must be drawn wherever necessary.
- 3) Use of electronic pocket calculator is allowed.
- 4) Assume suitable data, if necessary.

**Q1) a) Explain temperature effects in semiconductor. [7]**

**b) What is Lithography? Write different methods which are used for IC fabrication. [7]**

**c) What is Fin FET? How it is different than normal FET? [6]**

**OR**

**Q2) a) What are the different technologies which are used for silicon crystal growth? [7]**

**b) What is etching? What do you mean by wet etching and dry etching? [7]**

**c) Write short notes on : [6]**

**i) Dopant diffusion**

**ii) Sputtering**

**Q3) a) Discuss three different approaches for circuits that can be integrated with MEMS. [9]**

**b) What is Encapsulation? Explain Importance of it. [9]**

**OR**

**Q4) a) Explain experimental methods for measuring intrinsic stress. [9]**

**b) Write a short note on [9]**

**i) Sensor**

**ii) Actuator**

**iii) Transducer**

**P.T.O.**

- Q5)** a) What is direct and inverse effect of piezo electric sensors? [8]  
b) Compare electrostatic and thermal actuation methods. [8]

OR

- Q6)** a) What are the aspects, which should be considered for successful design of accelerometer. [8]  
b) Write short note on comb drive devices. [8]

- Q7)** a) Write short note on [8]  
i) Profilo meter  
ii) Reflectometer  
b) What are the advantages and disadvantages of Transmission Electron Microscopy (TEM) in comparison to Scanning Electron Microscopy (SEM). [8]

OR

- Q8)** a) What is FTIR? Explain advantages, limitations and applications FTIR. [8]  
b) Write short note on Atomic Force Microscope. (AFM) [8]

